

文件编号HXA-L20-24(01)发行日期2015年11月05日

承认规格书

种类:功率电感

系列号: <u>HXNR5020N-Series</u>

客户料号:_____

李	客户承 认栏			
承认日期	年	月	日	

(贵司承认后请签署一份返回华信安电子,谢谢!)

厦门华信安电子科技有限公司技术质量部

承 认	确认	作成
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Power Inductor

HXNR5020N-SERIES

		ECN HISTORY	ECN HISTORY LIST					
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN			
1.0	15/11/05	新 發 行	龙梅	梁峰	王亮			
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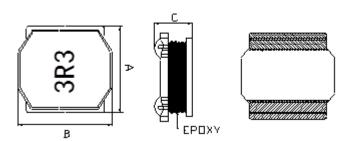
Power Inductor

HXNR5020N-SERIES

1. Features

- 1. This specification applies Low Profile Power Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant.

2. Dimension

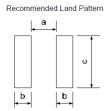


Series	A(mm)	B(mm)	C(mm)	
HXNR5020N	5.0±0.2	5.0±0.2	2.0 Max	

Halogen-free



Recommendend Land pattern



а Тур	b Тур	с Тур
2.3	1.4	4.2

3. Part Numbering

HXNR 5020 N - 1R0 Y
A B C D E

A: Series

B: Dimension

C: Control S/N

D: Inductance 1R0=1.0uH

E: Inductance Tolerance $M=\pm 20\%$; $Y=\pm 30\%$

4. Specification

ISND Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	SRF (MHz) min.	DCR (Ω) ±20%	I sat (A)	I rms (A)
HXNR5020N-1R0Y	1.0	±30%	1V100K	81	0.021	4.00	3.60
HXNR5020N-1R5Y	1.5	±30%	1V100K	68	0.026	3.35	3.20
HXNR5020N-2R2Y	2.2	±30%	1V100K	57	0.035	2.90	2.90
HXNR5020N-3R3Y	3.3	±30%	1V100K	46	0.048	2.40	2.40
HXNR5020N-4R7M	4.7	±20%	1V100K	37	0.060	2.00	2.00
HXNR5020N-6R8M	6.8	±20%	1V100K	30	0.090	1.60	1.65
HXNR5020N-100M	10	±20%	1V100K	24	0.120	1.30	1.45
HXNR5020N-150M	15	±20%	1V100K	20	0.165	1.10	1.20
HXNR5020N-220M	22	±20%	1V100K	17	0.260	0.90	1.00

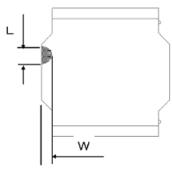
Note:

Isat : Based on inductance change (△L/L0 : ≦-30%) @ ambient temp. 25°C

Irms : Based on temperature rise $(^{\triangle}T : 40^{\circ}C \text{ typ.})$

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Core chipping

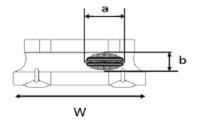


Туре	L	w	
HXNR5020N	1.5mm Max.	1.5mm Max.	

The appearance standard of the chipping size in top side, of bottom side ferrite core is following dimension.

Void appearance tolerance Limit

Size of voids occurring to coating resin is specified below.



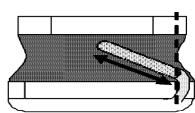
External appearance criterion for exposed wire

Exposed end of the winding wire at the secondary side should be 3mm and below.

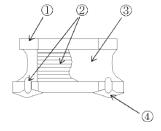
Exposed wire tolerance limit of coating resin part on product side.

Size of exposed wire occurring to coating resin is specified below.

- 1. Width direction (dimension a) : Acceptable when a \leq w/2 Nonconforming when a > w/2
- 2. Length direction (dimension b): Dimension b is not specified.
- 3. When total area of exposed wire occurring to each sides is not greater than 50% of coating resin area, that is acceptable.



5. Material List



No.	Item	Material
1	Core	Ni-Zn ferrite
2	2 Wire Copper Wire	
3	3 Coating Epoxy	
4	Solder	Lead free

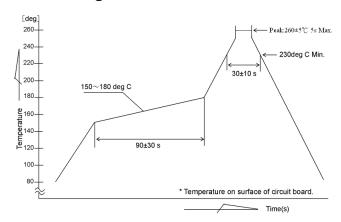
6. Reliability and Test Condition

Item	Performance	Test Method and Remarks
Operating Temperature	- 25 ~ +125°C.	Including self-generated heat
Storage Temperature	-40 \sim +85 $^{\circ}\mathrm{C}$ 5 to 40 $^{\circ}\mathrm{C}$ for the product with taping.	
Rated current		
Inductance (L)	Within the specified tolerance	LCR Meter: HP 4285A or equivalent, 100kHz, 1V
DC Resistance		DC Ohmmeter: HIOKI3227 or equivalent
Temperature characteristics	Inductance change: Within±20%	Measurement of inductance shall be taken at temperature rang within–25°C to +85°C. With reference to inductance value at+20 °C, change rate shall be calculated. Measurement of inductance shall be taken at temperature rang within–40°C to +125°C. With reference to inductance value at+20 °C, change rate shall be calculated.
Resistance to flexure substrate	No damage.	The test samples shall be soldered to the testing board by the reflow. As illustrated below, apply force in the direction of the arrow indicating until deflection of the test board reaches to 2mm. Procedure Board Board Float Float Board Float Float Board Float Float Board Float F
Adhesion of Terminal electrode	Shall not come off PC board.	The test samples shall be soldered to the testing board and by the reflow. 10 N, 5 s Applied force : 10 N to X and Y directions. Duration : 5s Solder cream thickness : 0.15
Resistance to Vibration	Inductance change: Within±10% No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow. Then it shall be submitted to below test conditions. Frequency: 10-55Hz Total Amplitude: 1.5mm (May not exceed acceleration 196m/S2) Sweeping Method:10Hz to 55Hz to 10Hz for 1min. Time: 2 hours each in X,Y, and Z Direction. Recovery: At least 2hrs of recovery under the standard condition after the test, followed by the measurement within 48hrs.
Solderability	At least 90% of surface of terminal electrode is covered by new solder.	The test samples shall be dipped in flux, and then immersed in molten solder as shown in below. Flux: methanol solution containing rosin 25% Solder temperature: 245±5°C Time: 5±1.0 sec. Immersion depth: All sides of mounting terminal shall be immersed.

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Item	Performance		Test Method and R	emarks	
Resistance to soldering		ample shall be exposed to reflow oven at 230±5°C onds, with peak temperature at 260±5°C for 5 times. I thickness: 1.0mm material: glass epoxy-resin			
		reflow. The test sam for specified to sequence.	ples shall be soldered to ples shall be placed at time by step 1 to step 4 ture cycles shall be rep	specified tempera as shown below	ature in
Thermal shock		Phase	Temperature(℃)	Time(min.)	
		1	-40±3℃	30±3	
		2	RoomTemp	Within 3	
		3	85±2°C	30±3	1
		4	RoomTemp	Within 3]
Damp heat life test	Inductance change: Within±10% No abnormality observed in appearance.	Test Method and Remarks The test samples she soldered to the test board by the reflow. The test samples shall be placed in thermostatic specified temperature and humidity as shown in Temperature: 60±2°C Humidity: 90–95%RH Time: 500+24/-0 hrs			set at
Loading under damp heat life test		reflow. The test sam specified tem current contir Temperature: Humidity: 90-	-95%RH ent: Rated current	thermostatic oven	set at
Low temperature life test		The test samples shall be soldered to the test board in reflow. After that, the test samples shall be placed at test corrus shown in below. Temperature:-40±2°C Time:500+24/-0 hrs			
Loading at high temperature life test		reflow. Temperature:	ent: Rated current	o the test board b	by the

7. Soldering

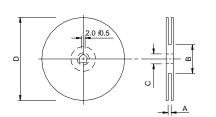


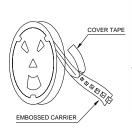
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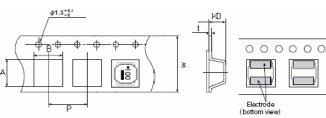
(2) Tape Dimension

8. Packaging Information

(1) Reel Dimension







Туре	Type A(mm) B(mm)		C(mm)	D(mm)	
HXNR5020N	14±1.5	60±2.0	13±0.5	180±3.0	

Туре	A(mm)	B(mm)	Ko(mm)	P(mm)	W(mm)	t(mm)
HXNR5020N	5.25±0.1	5.25±0.1	2.3±0.1	8.0±0.1	12±0.3	0.3±0.1

(3) Packaging Quantity

Туре	Chip / Reel
HXNR5020N	2500

Application Notice

Storage Conditions

To maintain the solderability of terminal electrodes:

- 1. ISND products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 2. Temperature and humidity conditions: Less than 40 $^{\circ}\text{C}\,$ and 60% RH.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- ·Transportation
 - $1. \ Products \ should \ be \ handled \ with \ care \ to \ avoid \ damage \ or \ contamination \ from \ perspiration \ and \ skin \ oi \ ls.$
 - 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
 - 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

单击下面可查看定价,库存,交付和生命周期等信息

>>ISND(华信安)